

# APPROVAL SHEET

MULTILAYER CERAMIC CAPACITORS

Ultra-small Series (6.3V to 50V)

01005 Size

NP0, X7R & X5R Dielectrics

Halogen Free & RoHS Compliance

\*Contents in this sheet are subject to change without prior notice.

#### **Multilayer Ceramic Capacitors**



Approval Sheet

#### 1. INTRODUCTION

MLCC consists of a conducting material and electrodes. To manufacture a chip-type SMT and achieve miniaturization, high density and high efficiency, ceramic condensers are used.

01R5 MLCC is performed by high precision technology achieve high capacitance in unit size and ensure the stability and reliability of products.

# 2. FEATURES

- a. High capacitance in unit size.
- b. High precision dimensional tolerances.
- c. Suitable used in high-accuracy automatic mounting machine.

### 3. APPLICATIONS

- a. Miniature microwave module.
- b. Portable equipments (ex. Mobile phone, PDA).
- c. High frequency circuits.

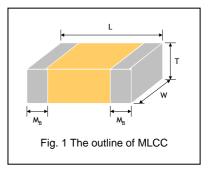
# **4. HOW TO ORDER**

<u>01R5</u>	<u>N</u>	<u>100</u>	<u>C</u>	<u>160</u>	<u>C</u>	I
<u>Size</u>	<u>Dielectric</u>	<u>Capacitance</u>	<u>Tolerance</u>	Rated voltage	<u>Termination</u>	<u>Packaging</u>
		14.	斩月	13 2		
Inch (mm)	N=NP0	Two significant digits	<b>A</b> =±0.05pF	Two significant digits	<b>C</b> =Cu/Ni/Sn	T=7" reeled
01R5 =	(C0G)	followed by no. of zeros.	<b>B</b> =±0.1pF	followed by no. of		
<b>01005</b> (0402)	<b>B</b> =X7R	And R is in place of	<b>C</b> =±0.25pF	zeros. And R is in		
	<b>X</b> =X5R	decimal point	<b>D</b> =±0.5pF	place of decimal point.		
		HHI?	F=±1%	V.,,		
		eg.:	G=±2%	<b>6R3</b> =6.3 VDC		
		0R5=0.5pF	<b>J</b> =±5%	<b>100</b> =10 VDC		
		1R0=1.0pF	<b>K</b> =±10%	<b>160</b> =16 VDC		
		100=10x10 <sup>0</sup>	<b>M</b> =±20%	<b>160</b> =16 VDC <b>250</b> =25 VDC		
		=10pF		<b>500</b> =50 VDC		
		CIN 1	9ch	CO160 (1)		

# **5. EXTERNAL DIMENSIONS**

Size Inch (mm)	L (mm)	W (mm)	T (mm)/Symbol		M <sub>B</sub> (mm)
01R5 (0402)	0.40±0.02	0.20±0.02	0.20±0.02	V	0.10±0.03

<sup>\*</sup> Reflow soldering only.



# **6. GENERAL ELECTRICAL DATA**

Size	01R5				
Dielectric	NP0	X7R	X5R		
Capacitance*	0.2pF to 100pF	100pF to 1000pF	1000pF to 0.1μF		
Capacitance tolerance**	Cap≤5pF: A (±0.05pF), B (±0.1pF), C (±0.25pF) 5pF <cap<10pf: C (±0.25pF), D (±0.5pF) Cap≥10pF: F (±1%), G (±2%), J (±5%)</cap<10pf: 	Л (±20%)			
Rated voltage (WVDC)	16V, 25V, 50V	_10V	6.3V, 10V		
DF / Q <sup>#1</sup>	Cap<30pF, Q≥400+20C Cap≥30pF, Q≥1000	≤5 %	≤10 %		
Insulation resistance at Ur	≥10GΩ or RxC≥500Ω*F whichever is less		RxC≥50Ω*F		
Operating temperature	<55 to +125℃ SSIVE SYST	<sup>EM</sup> ALLIA55 to +125℃	-55 to +85℃		
Capacitance change	±30ppm	±159	%		
Termination	Ni/Sn (lead-free termination)				

<sup>\*</sup> Measured at 30~70% related humidity.

NP0: Apply 0.5~5Vrms, 1.0MHz±10% at the condition of 25℃ ambient temperature.

X7R: Apply 1.0±0.2Vrms, 1.0kHz±10%, at 25°C ambient temperature.

X5R: Apply 0.5±0.2Vrms or 1.0±0.2Vrms <sup>#1</sup>, 1.0kHz±10%, at the condition of 25°C ambient temperature.

#1: Please refer to "RELIABILITY TEST CONDITIONS AND REQUIREMENTS" for detail

<sup>\*\*</sup> Preconditioning for Class II MLCC: Perform a heat treatment at 150±10°C for 1 hour, then leave in a mbient condition for 24±2 hours before measurement.

# 7. CAPACITANCE RANGE

	SIZE		01R5		
	DIELECTRIC		NP0		
RAT	ED VOLTAGE (VDC)	16	25	50	
	0.2pF (0R2)	V	V	V	
	0.3pF (0R3)	V	V	V	
	0.4pF (0R4)	V	V	V	
	0.5pF (0R5)	V	V	V	
	1.0pF (1R0)	V	V	V	
	1.5pF (1R5)	V	V	V	
	2.0pF (2R0)	V	V	V	
	3.0pF (3R0)	V	V	V	
	4.0pF (4R0)	V	V	V	
	5.0pF (5R0)	V	V	V	
	6.0pF (6R0)	V	V	V	
ည	7.0pF (7R0)	V	V	V	
tar	8.0pF (8R0)	V	V	V	
aci	9.0pF (9R0)	V	V	V	
Capacitance	10pF (100)	V	V	V	
ပ	12pF (120)	V	V	V	
	15pF (150)	V	V	V	
	18pF (180)	V	V	V	
	22pF (220)	V	V	V	
	27pF (270)	V	V	V	
	33pF (330)	V	V	V	
	39pF (390)	V	V	V	
	47pF (470)	V 	V	V	
	56pF (560)	V	V	// V	
	68pF (680) 82pF (820)		V	V	
	100pF (101)	V	V 22/	V	

SIZE		01R5
	DIELECTRIC	X7R
R.A	TED VOLTAGE (VDC)	10
	100pF (101)	V
Capacitance	150pF (151)	V
itaı	220pF (221)	V
oac	330pF (331)	V
Cap	470pF (471)	V
	1,000pF (102)	V

	SIZE	01R5		
	DIELECTRIC	X5R		
R/	ATED VOLTAGE (VDC)	6.3	10	
	1,000pF (102)	V	V	
	1,500pF (152)		V	
	2,200pF (222)		V	
	3,300pF (332)		V	
Се	4,700pF (472)		V	
an	6,800pF (682)		V	
Capacitance	0.010µF (103)	V	V	
ape	0.015µF (153)			
ပိ	0.022µF (223)	V		
	0.033µF (333)	V		
	0.047µF (473)	V		
	0.068µF (683)			
	0.10µF (104)	V		

- 1. The letter in cell is expressed the symbol of product thickness.
- 2. For more information about products with special capacitance or other data, please contact WTC local representative.

# 8. PACKAGING DIMENSION AND QUANTITY

Ci	Thickness (mm)/Symbol		Paper tape	
Size			7" reel	13" reel
01R5 (0402)	0.20±0.02	V	20,000	-

Unit: pieces



# 9. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

No.	Item	Test Condition	Requirements
1.	Visual and Mechanical		* No remarkable defect. * Dimensions to conform to individual specification sheet.
	Capacitance Q/ D.F. (Dissipation Factor)	*Test temp.: Room Temperature.  Class I: NP0  Cap≤1000pF, 0.5~5Vrms, 1MHz±10%  Cap>1000pF, 1.0±0.2Vrms, 1KHz±10%  Class II: , X7R & X5R(≥10V)  1.0±0.2Vrms, 1KHz±10%  Class II: , X5R(≤6.3V)  0.5±0.2Vrms, 1kHz±10%  *Before initial measurement (Class II only): To apply de-aging at 150℃ for 1hr then set for 24±2 hrs at room temp .	* Shall not exceed the limits given in the detailed spec.  * NP0: Cap≥30pF, Q≥1000; Cap<30pF, Q≥400+20C  X7R: ≤5.0 %  X5R: ≤10 %
4.	Dielectric Strength	* To apply voltage (≤100V) 250%. * Duration: 1 to 5 sec. * Charge and discharge current less than 50mA.	* No evidence of damage or flash over during test.
	Insulation Resistance	*Test temp.: Room Temperature.  *To apply rated voltage for max. 120 sec.	* NP0, X7R: ≥10GΩ or RxC≥500Ω-F whichever is smaller. X5R: RxC≥50Ω-F
6.	Temperature Coefficient	With no electrical load.  T.C. Operating Temp  NPO -55~125°C at 25°C  X7R -55~125°C at 25°C  X5R -55~ 85°C at 25°C  *Before initial measurement (Class II only):  To apply de-aging at 150°C for 1hr then set for 24± 2 hrs at room temp.  *Measurement voltage for Class II  Cap≤0.01µF: 0.5∨  Cap>0.01µF: 0.2∨	T.C. Capacitance Change  NPO Within ±30ppm/°C  X7R Within ±15%  X5R Within ±15%
7.	Adhesive Strength of Termination	* Pressurizing force : 1N * Test time: 10±1 sec.	* No remarkable damage or removal of the terminations.
8.	Vibration Resistance	* Vibration frequency: 10~55 Hz/min.  * Total amplitude: 1.5mm  * Test time: 6 hrs. (Two hrs each in three mutually perpendicular directions.)  * Before initial measurement (Class II only):  To apply de-aging at 150℃ for 1hr then set for 24±2 hrs at room temp.  * Cap./DF(Q) Measurement to be made after de-aging at 150℃ for 1hr then set for 24±2 hrs at room temp.	* No remarkable damage. * Cap change and Q/D.F.: To meet initial spec.
9.	Solderability	* Solder temperature: 235±5°C  * Dipping time: 2±0.5 sec.	95% min. coverage of all metalized area.
10.	Bending Test	* The middle part of substrate shall be pressurized by means of the pressurizing rod at a rate of about 1 mm per second until the deflection becomes 1 mm and then the pressure shall be maintained for 5±1 sec.  * Before initial measurement (Class II only): To apply de-aging at 150°C for 1hr then set for 24±2 hrs at room temp.  * Measurement to be made after keeping at room temp. for 24±2 hrs.	* No remarkable damage.  * Cap change:  NP0: within ±5.0% or ±0.5pF whichever is larger.  X7R: within ±12.5%  X5R: within ±25.0%  (This capacitance change means the change of capacitance under specified flexure of substrate from the capacitance measured before the test.)

<sup>\* &</sup>quot;Room condition" Temperature: 15 to 35°C, Relativ e humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

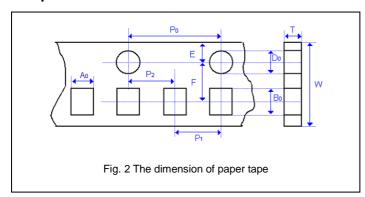
# **Multilayer Ceramic Capacitors**

No.	Item	Test Condition	Requirements	
11.	Resistance to Soldering Heat	* Solder temperature: 260±5°C  * Dipping time: 10±1 sec  * Preheating: 120 to 150°C for 1 minute before imme rse the capacitor in a eutectic solder.  * Before initial measurement (Class II only): To apply de-agir at 150°C for 1hr then set for 24±2 hrs at room temp.  * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp.	* No remarkable damage.  * Cap change:  NP0: within ±2.5% or ±0.25pF whichever is larger.  X7R: within ±7.5%  X5R: within ±15.0%  Q/D.F., I.R. and dielectric strength: To meet initial requirements.  * 25% max. leaching on each edge.	
12.	Temperature Cycle	* Conduct the five cycles according to the temperatures and time.    Step   Temp. (°C)   Time (min.)     1   Min. operating temp. +0/-3   30±3     2   Room temp.   2~3     3   Max. operating temp. +3/-0   30±3     4   Room temp.   2~3     * Before initial measurement (Class II only): To apply de-aging at 150°C for 1hr then set for 24±2 hrs at room temp.     * Cap. / DF(Q) / I.R. Measurement to be made after de-aging temps.	* No remarkable damage.  * Cap change: NP0: within ±2.5% or ±0.25pF whichever is larger. X7R: within ±7.5% X5R: within ±15.0%  * Q/D.F., I.R. and dielectric strength: To meet initial requirements.	
	Humidity (Steady State)	at 150℃ for 1hr then set for 24±2 hrs at room temp.  * Test temp.: 40±2℃  * Humidity: 90~95% RH  * Test time: 500+24/-0hrs.  * Before initial measurement (Class II only): To apply de-agir at 150℃ for 1hr then set for 24±2 hrs at room temp.  * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150℃ for 1hr then set for 24±2 hrs at room temp.	X5R: within ±25.0%	
14.	Humidity Load (Damp Heat)	* Test temp.: 40±2°C  * Humidity: 90-95%RH  * Test time: 500+24/-0 hrs.  * To apply voltage: rated voltage.  * Before initial measurement (Class II only): To apply de-agir at 150°C for 1hr then set for 24±2 hrs at room temp.  * Cap. / DF(Q) / I.R. Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp.	* Q/D.F. value: NP0: Cap≥30pF, Q≥200; Cap<30pF; Q≥100+10/3C X7R: ≤7.5%	
15.	High Temperature Load (Endurance)	* Test temp.:  NP0, X7R: 125±3°C  X5R: 85±3°C  * To apply voltage:  (1) NP0, X7R: 200% of rated voltage (2) X5R: 10V: 150 % of rated voltage 6.3V: 100 % of rated voltage  * Test time: 1000+24/-0 hrs.  * Before initial measurement (Class II only): To apply de-agir at 150°C for 1hr then set for 24±2 hrs at room temp.  * Cap. / DF(Q) / I.R. Measurement to be made after de-aging 150°C for 1hr then set for 24±2 hrs at room temp.  ** De-rating conditions:	* No remarkable damage. * Cap change: NP0: within ±3.0% or ±0.3pF whichever is larger.  X7R: within ±12.5%  X5R: within ±25.0%	

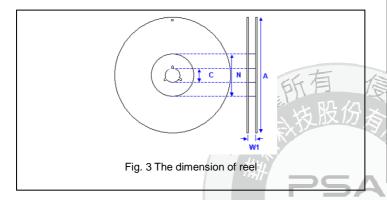
<sup>\* &</sup>quot;Room condition" Temperature: 15 to 35°C, Relative humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

# **APPENDIXES**

#### **■ Tape & reel dimensions**

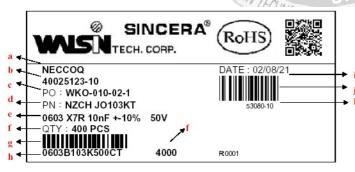


Size	01R5
Thickness	V
A <sub>0</sub>	0.25 +/-0.05
B <sub>0</sub>	0.45 +/-0.05
Т	≦0.50
K <sub>0</sub>	-
w	8.00 +/-0.30
P <sub>0</sub>	4.00 +/-0.10
10xP <sub>0</sub>	40.00 +/-0.10
<b>P</b> <sub>1</sub>	2.00 +/-0.05
P <sub>2</sub>	2.00 +/-0.05
D <sub>0</sub>	1.50 +0.1/-0
D <sub>1</sub>	-
E	1.75 +/-0.10
F	3.50 +/-0.05



A.	
Size	01R5
Reel size	7"
C	13.0±0.5
W <sub>1</sub>	10.0±1.5
X	178.0±2.0
N	60.0+1.0/-0

# **■** Example of customer label

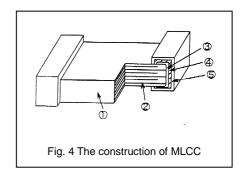


<sup>\*</sup>Customized label is available upon request

- a. Customer name
- b. WTC order series and item number
- c. Customer P/O
- d. Customer P/N
- e. Description of product
- f. Quantity
- g. Bar code including quantity & WTC P/N or customer
- h. WTC P/N
- i. Shipping date
- j. Order bar code including series and item numbers
- k. Serial number of label

#### Constructions

No.	Name		NP0	X7R, X5R
①	Ceramic material		CaZrO₃ based	BaTiO₃ based
2	Inner electrode		Ni	
3	Inner layer		C	u
4	Termination	Middle layer	Ni	
(5)		Outer layer	Sn (Matt)	



#### Storage and handling conditions

- (1) To store products at 5 to 40°C ambient temperature and 20 to 70%. related humidity conditions; MSL Level 1.
- (2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

#### Cautions:

- a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
- b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.
- c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.

# ■ Recommended soldering conditions

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of  $N_2$  within oven are recommended.

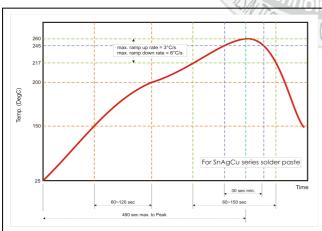


Fig. 5 Recommended reflow soldering profile for SMT process with SnAgCu series solder paste.

# **Mouser Electronics**

**Authorized Distributor** 

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# Walsin:

 01R5B102K100CT
 01R5N0R5B160CT
 01R5X104K6R3CT
 01R5N150J160CT
 01R5N120J160CT

 01R5N2R0C160CT
 01R5N3R0C160CT
 01R5N4R0C160CT
 01R5N5R0C160CT
 01R5N7R0D160CT

 01R5B101K100CT
 01R5B221K100CT
 01R5N100J160CT
 01R5N101J160CT
 01R5N101J250CT
 01R5N120J250CT

 01R5N180J160CT
 01R5N1R0C160CT
 01R5N1R2C160CT
 01R5N1R5C160CT
 01R5N1R8C160CT

 01R5N3R0A250CT
 01R5N3R3C160CT
 01R5N3R9C160CT
 01R5N470J160CT
 01R5N4R7C160CT

 01R5N5R0C250CT
 01R5N5R6C160CT
 01R5N6R0C160CT
 01R5N6R8C160CT
 01R5N6R8C160CT